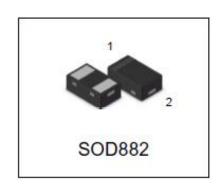


ESD3V3D8B

Description

The ESD3V3D8B in a SOD-882 package and will protect bidirectional line. These devices are designed to replace multilayer varistors (MLVs) in portable applications such as cell phones, notebook computers, and PDA's. They offer superior electrical characteristics such as lower clamping voltage and no device degradation when compared to MLVs, The ESD3V3D8B are designed to protect sensitive semiconductor components from damage or upset due to electrostatic discharge (ESD),and other voltage induced transient events.



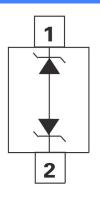
Feature

- Case: SOD882 package
- Low clamping voltage
- Low Leakage current
- Peak Power up to 150 Watts @ 8 x 20 µs Pulse
- Response Time is Typically < 1.0 ns
- IEC61000 4 2 Level 4 ESD Protection

Applications

- Cellular phones
- Portable devices
- Digital cameras
- Power supplies

Schematic & PIN Configuration



Absolute Maximum Ratings

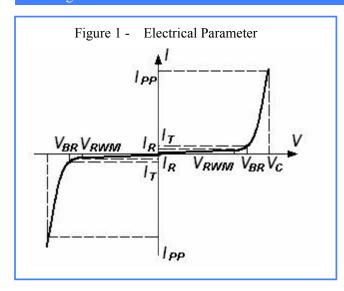
Parameter	Symbol	Value	Units	
IEC61000-4-2 (Contact)	$ m V_{ESD}$	8	kV	
IEC61000-4-2 (Air)	$ m V_{ESD}$	15	kV	
Lead Soldering Temperature	$T_{ m L}$	260 (10 sec)	° C	
Operating Temperature	T_{op}	-40 to 125	° C	
Storage Temperature Range	T_{STG}	-55 to 155	° C	
Maximum junction temperature	$T_{\rm j}$	150	° C	
Peak Pulse Power (tp = 8/20s)	P_{pk}	150	W	

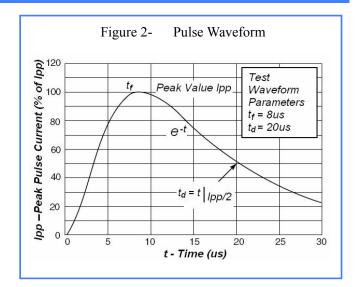


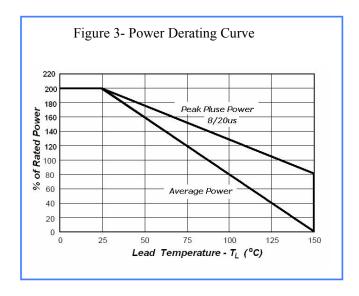
Electrical Characteristics (T =25° C)

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Units
Reverse Stand-off Voltage	V_{RWM}				3.3	V
Reverse Breakdown Voltage	V_{BR}	I _t = 1mA	5			>
Reverse Leakage Current	l _R	$V_R = V_{RWM}$			1	μ Α
Clamping Voltage	$V_{\rm C}$	I_{PP} =5A, t_P = 8/20 μ s		8.4		V
Peak pulse Current	I_{PP}	t _P = 8/20µs			11.2	А
Junction Capacitance	CJ	V _R =0V, f = 1MHz		25		pF

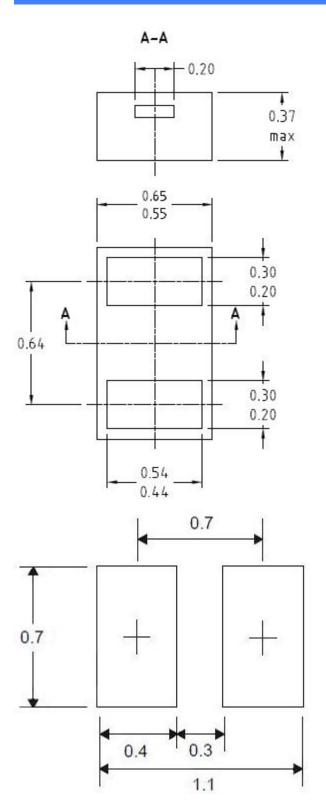
Rating & Characteristic Curves

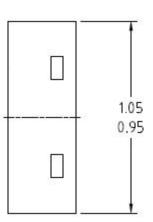






PACKAGE OUTLINE DIMENSIONS in millimeters: SOD882





Disclaimer

Specifications are subject to change without notice.

The device characteristics and parameters in this data sheet can and do vary in different applications and actual device performance may vary over time.

Users should verify actual device performance in their specific applications.